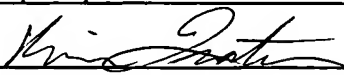


Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 111184.01		APPLICATION NO. Rule 53(b) Divisional of U.S. Application No. 09/991,984 filed November 26, 2001	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Shunichi SEKI et al.			
				FILING DATE February 26, 2004		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
Ka		6,087,196	07/2000	Sturm et al.	438	29	
Ka		5,903,246	05/1999	Dingwall	345	82	
Ka		6,580,212	06/2003	Friend	313	504	
Ka		6,163,352	12/2000	Ichikawa et al.	349	106	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
Ka		JP-A-7-235378 (w/English abstract)	09/05/95	Japan	—	—	
Ka		JP-A-10-12377 (w/English abstract)	01/16/98	Japan	—	—	
Ka		JP-A-10-153967 (w/English abstract)	06/09/98	Japan	—	—	
Ka		JP-A-11-40358 (w/English abstract)	02/12/99	Japan	—	—	
Ka		JP-A-11-54270 (w/English abstract)	02/26/99	Japan	—	—	
Ka		JP-A-11-339957 (w/English abstract)	12/10/99	Japan	—	—	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
Ka		TANG, C.W. et al., "Organic electroluminescent diodes", <i>Appl. Phys. Lett.</i> , Vol. 51, No. 12, September 21, 1987, pp. 913-915.					
Ka		SASAKI, Keiji et al., "Three-dimensional potential analysis of radiation pressure exerted on a single microparticle", <i>Appl. Phys. Lett.</i> , Vol. 71, No. 1, July 7, 1997, pp. 37-39.					
EXAMINER 				DATE CONSIDERED 12/11/04			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: February 26, 2004

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 111184.01		APPLICATION NO. Rule 53(b) Divisional of U.S. Application No. 09/991,984 Filed November 26, 2001	
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U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
Ka		2001/0009689	07/2001	Himeshima et al.	427	64
Ka		6,489,952	12/2002	Tanaka et al.	395	205

FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
Ka		JP 07-142169A and Eng. Trans.	6/2/1995	Japan	—	—
Ka		JP 2000-163014A and Eng. Trans.	6/16/2000	Japan	—	—
Ka		JP 2000-012238A and Eng. Trans.	1/14/2000	Japan	—	—
Ka		JP 11-121168A and Eng. Trans.	4/30/1999	Japan	—	—
Ka		JP 2002-022924A and Eng. Trans.	1/23/2002	Japan	—	—
Ka		JP 10-050481A and Eng. Trans.	2/20/1998	Japan	—	—
Ka		JP 2000-148090A and Eng. Trans.	5/26/2000	Japan	—	—
Ka		JP 2000-091083A and Eng. Trans.	3/31/2000	Japan	—	—
Ka		JP 2001-313182A and Eng. Trans.	11/9/2001	Japan	—	—
Ka		WO 01/78461A and US corresponding Patent Application No. US 2002175620	10/18/2001	Japan	—	—
Ka		WO0059267	10/2000	PCT	—	—
Ka		EP 1083775 A1	03/2001	European	—	—

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)	
Ka	European Search Report, dated May 28, 2003. <div style="border: 1px solid black; height: 20px; margin-bottom: 5px;"></div> <div style="border: 1px solid black; height: 20px; margin-bottom: 5px;"></div> <div style="border: 1px solid black; height: 20px; margin-bottom: 5px;"></div>

EXAMINER <i>Kristen</i>	DATE CONSIDERED 12/11/04
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